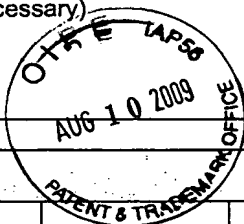


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2627

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## U.S. PATENT DOCUMENTS

Ref. Desig.	Examiner's Initials	Document Number	Date	Name	Class/ Subclass	(If appropriate) Filing Date
1.		5,572,507	11/05/1996	Ozaki et al.		
2.		5,689,486	11/18/1997	Shimizu et al.		
3.		5,737,286	04/07/1998	Timmermans et al.		
4.		5,799,501	09/01/1998	Leonard et al.		
5.		6,021,199	02/01/2000	Ishibashi		
6.		6,223,247 B1	04/24/2001	Otsuka et al.		
7.		6,353,890 B1	03/05/2002	Newman		
8.		6,519,213 B1	02/11/2003	Song et al.		
9.		6,549,495 B1	04/15/2003	Spruit et al.		
10.		6,550,009 B1	04/15/2003	Uranaka et al.		
11.		6,664,526 B2	12/16/2003	Yokoi		
12.		6,885,629 B2	04/26/2005	Oshima et al.		
13.		6,930,977 B1	08/16/2005	Kondo et al.		
14.		2001/0036132 A1	11/01/2001	Kobayashi et al.		
15.		2002/0089920 A1	07/11/2002	Gotoh et al.		
16.		2002/0181358 A1	12/05/2002	Sako		
17.		2003/0012375 A1	01/16/2003	Sako et al.		
18.		2003/0053404 A1	03/20/2003	Kondo		
19.		2004/0120247 A1	06/24/2004	Lee et al.		
20.		2004/0151091 A1	08/05/2004	Ma et al.		
21.		2005/0099916 A1	05/12/2005	Jeon et al.		

## FOREIGN PATENT DOCUMENTS

Ref. Desig.	Examiner's Initials	Document Number	Date	Country	Class/ Subclass	Translation Yes	No
22.		EP 0 299 573 B1	01/18/1989	Europe		N/A	
23.		EP 0 807 929 A1	11/19/1997	Europe		N/A	

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APPLICANT

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FILING DATE

January 23, 2004

GROUP

2627

24.		EP 1 028 423 B1	08/16/2000	Europe		N/A	
25.		EP 1 067 540 A2	01/10/2001	Europe		N/A	
26.		EP 1 122 729 A1	08/08/2001	Europe		N/A	
27.		EP 1 152 412 A1	11/07/2001	Europe		N/A	
28.		EP 1 168 312 A1	01/02/2002	Europe		N/A	
29.		EP 1 229 537 A2	08/07/2002	Europe		N/A	
30.		JP 05-325193	12/10/1993	Japan		Abstract	
31.		JP 07-272282	10/20/1995	Japan		Abstract	
32.		JP 08-147704	06/07/1996	Japan		Abstract	
33.		JP 10-269577	10/09/1998	Japan		Abstract	
34.		JP 11/317002	11/16/1999	Japan		Abstract	
35.		JP 2000-149415	05/30/2000	Japan		Abstract	
36.		JP 2000-195049	07/14/2000	Japan		Abstract	
37.		JP 2000-195094	07/14/2000	Japan		Abstract	
38.		JP 2000-298941	10/24/2000	Japan		Abstract	
39.		JP 2001-243355	09/07/2001	Japan		Abstract	
40.		JP 2001-256678	09/21/2001	Japan		Abstract	
41.		JP 2001-332031	11/30/2001	Japan		Abstract	
42.		JP 2002-042347	02/08/2002	Japan		Abstract	
43.		JP 2002-163857	06/07/2002	Japan		Abstract	
44.		JP 2002-197789	07/12/2002	Japan		Abstract	
45.		WO 97/45836	12/04/1997	WIPO		N/A	
46.		WO 00/21085	04/13/2000	WIPO		N/A	
47.		WO 02/15183 A2	02/21/2002	WIPO		N/A	
48.		WO 02/37493 A1	05/10/2002	WIPO		Abstract	

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Date Considered:

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	APPLICANT	
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	FILING DATE	GROUP
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49.		WO 2004/095439 A1	11/04/2004	WIPO		N/A	
50.		WO 2004/066286 A1	08/05/2004	WIPO		N/A	

OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, etc.)		
Ref. Desig.	Examiner's Initials	
51.		International Search Report dated April 28, 2004 for Application No. PCT/KR2004/000081
52.		International Search Report dated May 6, 2004 for Application No. PCT/KR2004/000113
53.		International Search Report dated May 18, 2004 for Application No. PCT/KR2004/000109
54.		International Search Report dated May 18, 2004 for Application No. PCT/KR2004/000111
55.		Korean Office Action dated March 28, 2005 for Korean Application No. 10-2003-0004487
56.		Korean Office Action dated March 30, 2006 for Korean Application No. 10-2003-0004487
57.		European Office Action dated June 12, 2006 for European Application No. 04703541.5
58.		Chinese Office Action dated September 1, 2006 for Chinese Application No. 200480000399.8
59.		European Office Action dated September 22, 2006 for European Application No. 04703531.6
60.		European Office Action dated September 22, 2006 for European Application No. 06001615.1
61.		European Office Action dated November 24, 2006 for European Application No. 04705015.8
62.		Russian Office Action date January 30, 2007 for Russian Application No. 2006109209
63.		U.S. Office Action dated April 11, 2007 for U.S. Application No. 10/762,535
64.		U.S. Office Action dated April 17, 2007 for U.S. Application No. 10/762,538
65.		U.S. Office Action dated June 12, 2007 for U.S. Application No. 10/762,536
66.		Taiwanese Office Action dated July 10, 2007 for Taiwanese Application No. 95113498
67.		Japanese Office Action dated August 24, 2007 for Japanese Application No. 2006-500638
68.		U.S. Office Action dated October 9, 2007 for U.S. Application No. 10/762,516
69.		European Patent Office Action dated October 29, 2007 for European Application No. 06001616.9
70.		European Patent Office Action dated November 7, 2007 for European Application No. 07018289.4
71.		U.S. Office Action dated November 15, 2007 for U.S. Application No. 10/762,535

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2627

72.		U.S. Office Action dated November 19, 2007 for U.S. Application No. 10/762,536
73.		Japanese Patent Office Action dated January 16, 2008 for Japanese Application No. 2006-76406
74.		Japanese Patent Office Action dated January 16, 2008 for Japanese Application No. 2006-500635
75.		Japanese Patent Office Action dated January 16, 2008 for Japanese Application No. 2006-76383
76.		Japanese Patent Office Action dated January 16, 2008 for Japanese Application No. 2006-500639
77.		European Patent Office Action dated March 12, 2008 for European Application No. 04703529.0
78.		Japanese Patent Office Action dated August 24, 2007 for Japanese Application No. 2006-500638
79.		Japanese Patent Office Action dated March 24, 2008 for Japanese Application No. 2006-500637
80.		European Patent Office Action dated March 26, 2008 for European Application No. 070184-5.6
81.		European Patent Office Action dated April 2, 2008 for European Application No. 04703277.6
82.		U.S. Office Action dated June 6, 2008 for U.S. Application No. 10/762,535

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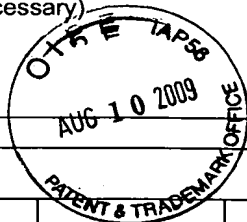
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**U.S. PATENT DOCUMENTS**

Ref. Desig.	Examiner's Initials	Document Number	Date	Name	Class/ Subclass	(If appropriate) Filing Date
		US 6,708,299 = KR 2001-0051834	03/16/2004	XIE		

**FOREIGN PATENT DOCUMENTS**

Ref. Desig.	Examiner's Initials	Document Number	Date	Country	Class/ Subclass	Translation Yes	No
		EP 0 898 271 = JP 11-066739	02/24/1999	EUROPE			X
		JP 11-066739	03/09/1999	JAPAN		Abstract	
		JP 2001-135021	05/18/2001	JAPAN		Abstract	
		JP 2001-344765	12/14/2001	JAPAN		Abstract	
		JP 2002-203374	07/19/2002	JAPAN		Abstract	
		JP 2002-311976	10/25/2002	JAPAN		Abstract	
		KR 2001-0051834	06/25/2001	KOREA		Abstract	

**OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, etc.)**

Ref. Desig.	Examiner's Initials	
		Office Action for corresponding Japanese Application No. 2008-319384 dated July 14, 2009.
		Office Action for corresponding Korean Application No. 10-2003-0005211 dated July 18, 2009.
		Office Action for corresponding Japanese Application No. 2006-500631 dated July 21, 2009.

Examiner:

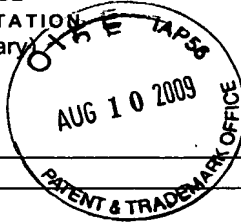
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Ref. Desig.	Examiner's Initials	Document Number	Date	Name	Class/ Subclass	(If appropriate) Filing Date

**FOREIGN PATENT DOCUMENTS**

Ref. Desig.	Examiner's Initials	Document Number	Date	Country	Class/ Subclass	Translation Yes	No
		JP 2000-231722	08/22/2000	JAPAN		Abstract	

**OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, etc.)**

Ref. Desig.	Examiner's Initials	
		Office Action for Japanese Application No. 2006-500637 dated June 16, 2009.

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